

REQUISITION FORM

Central Sophisticated Instrumentation Facility (CSIF)
Birla Institute of Technology & Science, Pilani – K. K. Birla Goa Campus
NH-17B Zuari Nagar – 403726, GOA, INDIA
Field Emission Scanning Electron Microscope /Scanning Transmission Microscope Facility
(Quanta FEG-250)

USER INFORMATION (INTERNAL USERS)

User Name:

Unique ID (UIN):

SAMPLE INFORMATION

Have sampling modalities and requirements discussed with the operator (Y/N):

S. No.	Sample code* (UIN – X*)	Nature of Samples : Metal / Film / Crystal / Biological / Ceramic / Tissue / Others:	Nature of the Analysis (SEM, EDX STEM etc.)	Sputter coating required (YES/NO)	Fixation and Dehydration /CPD/Trimming And Sectioning and standing /required (Yes/NO)

*where X is S1, S2 ..so on.

Please provide any other important information on a separate sheet (e.g. toxic samples)

PREFERRED SLOT TIMING:

I certify that my samples **do not** present any danger to the personnel or equipment and **I have provided the appropriate handling instructions for safety to the operator before analysis. I hereby declare that no radioactive sample has been forwarded for analysis.** I also certify that I shall acknowledge the FESEM/STEM facility at the Birla Institute of Technology & Science, Pilani K K Birla Goa Campus if the results are published in journals/conferences or in thesis. I shall also forward the citation details to the In-charge of the CSIF by email within a month of such publication. I am aware that the Centre has no liability as to any loss/damage of my samples during storage/transport/imaging at the Centre. I accept all the terms and conditions of use and confirm adherence to all rules and regulations of the Centre with regard to sample analysis.

I/We shall acknowledge the CSIF BITS PILANI K K Birla Goa Campus while publishing / reporting the results in journals / conferences or elsewhere.

(User with date)

(Supervisor / HOD)
(for students & non-tenure track faculty)

(SEM operator)